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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/690,594	10/23/2003	Benoit Nadeau-Dostie	LVPAT066US	6739
26668	7590	06/06/2007	EXAMINER	
RIDOUT & MAYBEE LLP 100 MURRAY STREET 4TH FLOOR OTTAWA, ON K1N 0A1 CANADA			KERVEROS, JAMES C	
			ART UNIT	PAPER NUMBER
			2117	
			MAIL DATE	DELIVERY MODE
			06/06/2007	PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Office Action Summary

Application No.

10/690,594

Applicant(s)

NADEAU-DOSTIE ET AL.

Examiner

JAMES C. KERVEROS

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-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

- 1) ☒ Responsive to communication(s) filed on 01 May 2007.
- 2a) ☒ This action is **FINAL**. 2b) ☐ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

- 4) ☒ Claim(s) 56 is/are pending in the application.
- 4a) Of the above claim(s) _____ is/are withdrawn from consideration.
- 5) ☒ Claim(s) 32-40 and 56 is/are allowed.
- 6) ☒ Claim(s) 1-31 and 41-54 is/are rejected.
- 7) ☒ Claim(s) 55 is/are objected to.
- 8) ☐ Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☒ The drawing(s) filed on 05 March 2004 is/are: a) ☒ accepted or b) ☐ objected to by the Examiner.
- Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).
- Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
- 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

- 12) ☒ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☒ All b) ☐ Some * c) ☐ None of:
1. ☒ Certified copies of the priority documents have been received.
 2. ☐ Certified copies of the priority documents have been received in Application No. _____.
 3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

* See the attached detailed Office action for a list of the certified copies not received.

Attachment(s)

- | | |
|--------------------------------------------------------------------------------------|-------------------------------------------------------------------|
| 1) <input type="checkbox"/> Notice of References Cited (PTO-892) | 4) <input type="checkbox"/> Interview Summary (PTO-413) |
| 2) <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948) | Paper No(s)/Mail Date. _____ |
| 3) <input type="checkbox"/> Information Disclosure Statement(s) (PTO/SB/08) | 5) <input type="checkbox"/> Notice of Informal Patent Application |
| Paper No(s)/Mail Date. _____ | 6) <input type="checkbox"/> Other: _____ |

DETAILED ACTION

This is a FINAL Office Action in response to the Amendment filed 5/1/2007.

Claims 1-56 are still pending in the Application.

Acknowledgment is made of applicant's claim for foreign priority under 35 U.S.C. 119(a)-(d) to CANADA 2,414,632, filed 12/18/2002. The certified copy has been filed in parent Application No. 10/690,594 on 10/23/2003.

The drawings, Replacement Sheets 4-6 received on March 5, 2004, are acceptable.

Response to Arguments

Applicant's arguments filed 5/1/2007, with respect to claims 1-31 and 41-54, have been fully considered but they are not persuasive.

Applicant argues that Heaslip does not anticipate independent claim 1, which recites "selectively generating a failure summary on-circuit while performing testing, and transferring the failure summary from the circuit under control of a second clock concurrently with testing of the next column or row in sequence".

In response to Applicant's argument, clearly, Heaslip discloses detecting memory failures during the comparison of BIST operations, using a read compare register 255 to compare the data read back from the arrays to the data written. When the read compare determines that the data-out from the register does not match the expected result (based upon the data-in from the data generator), a defective memory element has been found. With the invention, when such a condition occurs the compare

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logic 255 sends a signal to gate off the BIST clock 241 in that cycle as shown in Fig. 1.

Therefore, BIST operations stop after detection or generation of failures.

In reference to Applicant's argument, with respect to Heaslip, Fig. 2, in step 33 the BIST is initialized. In step 34, it begins clocking the BIST machine, which writes and reads the array. When a failing address is detected, in step 35, the BIST changes the test mode to scan so the failing data and address can be unloaded from the diagnostic register 251 to tester fail memory. Accordingly, the BIST changes from the test mode to the scan mode, only after a failing address is detected. Therefore, the BIST is still operational during failure detection.

In response to Applicant's argument, that Heaslip neither discloses nor remotely suggests scanning out a "failure summary" which could contain information about several failures in a row or column, Heaslip uses on chip BIST clock gating that immediately disables the clocks when the BIST compare circuitry detects a fail, which is then detected at the external tester pin a few cycles after it occurred to map the failing array's with AC faults. This allows the tester to run and detect fails at its slower speeds. The tester detects the fails and scans the diagnostic register for the failing address and data information, (see, Fig. 1 and Col. 2, lines 40-64).

Furthermore, the feature, failure summary containing information about several failures in a row or column, as recited in Applicant's arguments, is described in the specification, as "failure address registers store the row or column address of selected failures". It is noted that the feature upon which applicant relies is not recited in the rejected claims. Although the claims are interpreted in light of the specification,

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limitations from the specification are not read into the claims. See *In re Van Geuns*, 988 F.2d 1181, 26 USPQ2d 1057 (Fed. Cir. 1993).

Further, Heaslip discloses failures defective memory elements associated with rows or columns: "when the read compare determines that the data-out from the register does not match the expected result, a defective memory element has been found.

Claim Rejections - 35 USC § 102

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless –

(e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.

Claims 1-31, 41-54 are rejected under 35 U.S.C. 102(e) as being anticipated by Heaslip et al. (US-Patent 6,643,807) issued: November 4, 2003; filed: August 1, 2000.

Regarding independent Claims 1-31, 41-54, Heaslip discloses a method and apparatus including an array-built-in-self-test (ABIST) for efficient, fast, bitmapping of large embedded arrays in manufacturing test, which allows for bitmapping at speed, such as in real time, with the use of on chip clock generation (OPCG) with a phase lock

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loop (PLL) to clock the array BIST at high speeds. To map the failing array's with AC faults, Heaslip uses on chip BIST clock gating that immediately disables the clocks when the BIST compare circuitry detects a fail, which is then detected at the external tester pin a few cycles after it occurred. This allows the tester to run and detect fails at its slower speeds. The tester detects the fails and scans the diagnostic register for the failing address and data information, (see, Fig. 1 and Col. 2, lines 40-64). The method and apparatus comprising:

An embedded DRAM or SRAM under test for testing each memory cell of a row or column according to a memory test algorithm (from address and data generator 210 and 220, respectively) under the control of a first clock (BIST clock 241) generated by the on chip clock generation (OPCG) clock generator 240, which clocks the array BIST at high speeds.

Generating a failure summary (bitmapping at speed) using a read compare register 255 to compare the data read back from the arrays to the data written and a diagnostic register 251 to capture the compare output and failing address. The comparator identifies failed cycles where the retrieved data does not correspond correctly to the test data, and the diagnostic unit stores the failed cycles and being responsive to the controller regenerating and re-storing the test data in the read/write memory and stores the failed data and failing addresses.

Transferring the failure summary from the circuit under control of a second clock (tester external clock). The fail is detected at the external tester pin a few cycles after it occurred. This allows the tester to run and detect fails at its slower speeds. The tester

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detects the fails and scans the diagnostic register for the failing address and data information. Upon a completion of the fail data collection, the tester asserts the internal BIST clock back on and continues to the next failing address.

Allowable Subject Matter

Claims 32-40, 56 are allowed.

Claim 55 is objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

The following is a statement of reasons for the indication of allowable subject matter:

The prior arts of record taken alone or in combination fail to teach, anticipate, suggest or render obvious a method, as recited in the independent claim 32, including among other limitations, "classifying the detected failure according to predetermined failure types, and updating a failure mask register with results of comparisons of memory outputs and expected memory outputs".

Independent claim 56 recites, a memory test controller, including among other limitations, "failure type identification means responsive to a failure mask for classifying detected failures according to predetermined failure types, and counter means responsive to outputs of said failure type identification means for counting failures of each the predetermined types".

Also, claim 55 recites among other limitations, "a failure type identification circuit for determining a failure type of each detected failure, a failure type counter for each of said predetermined failure type, and a failure mask register for storing results of comparisons between each memory output and corresponding expected memory outputs".

Conclusion

THIS ACTION IS MADE FINAL. Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to JAMES C. KERVEROS whose telephone number is (571) 272-3824. The examiner can normally be reached on 9:00 AM TO 5:00 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Jacques H. Louis-Jacques can be reached on 571) 272-4150. The fax

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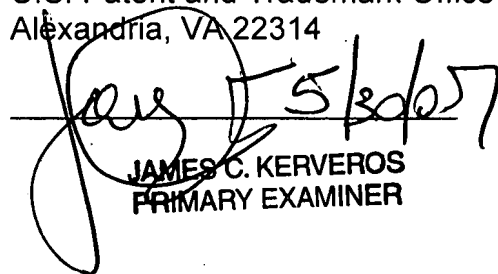
phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

Date: 30 May 2007
Office Action: Final Rejection

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 5/30/07
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